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Fig. 1

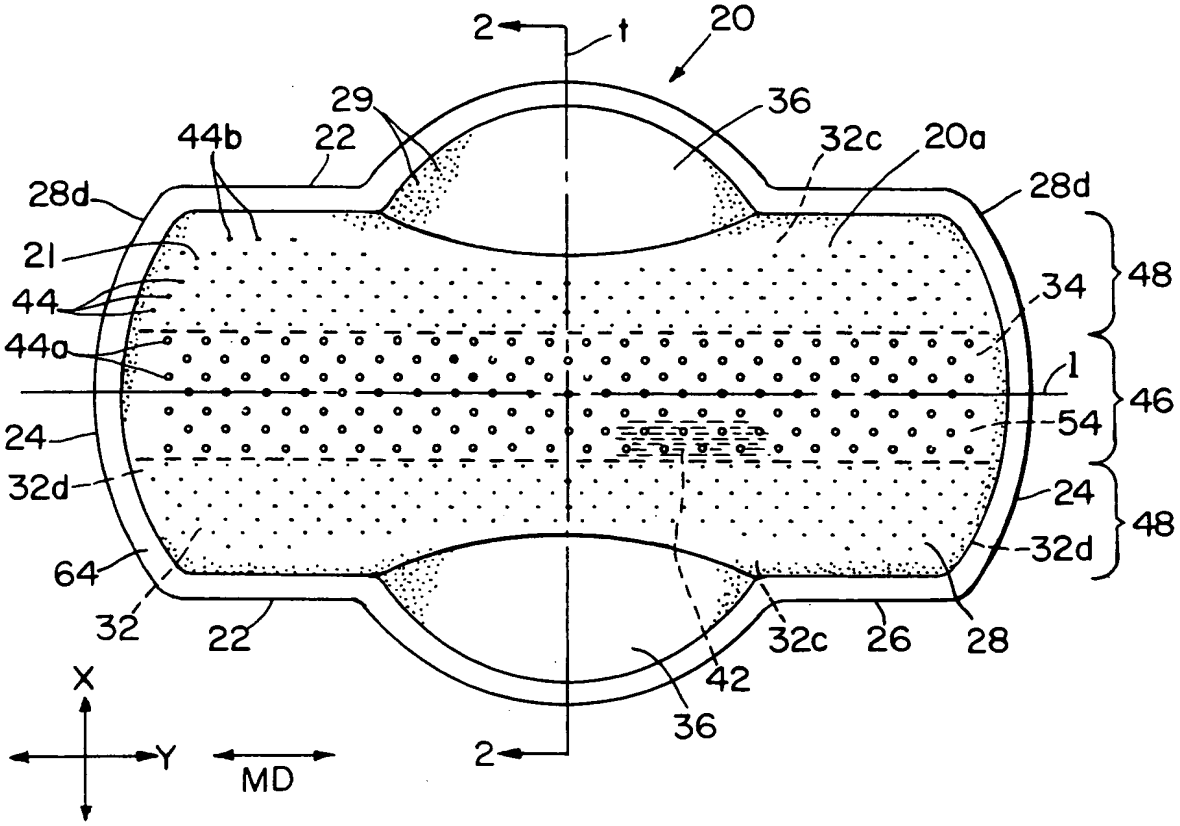
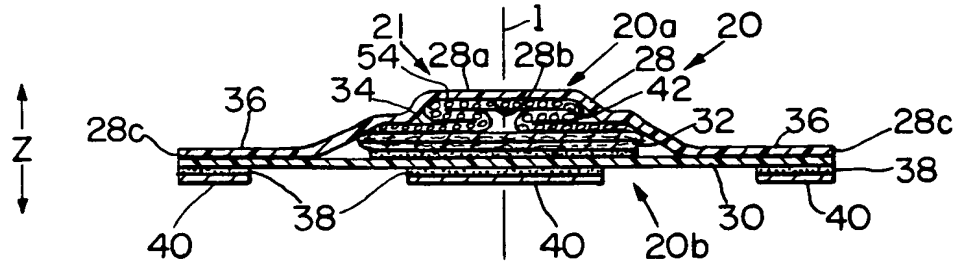


Fig. 2



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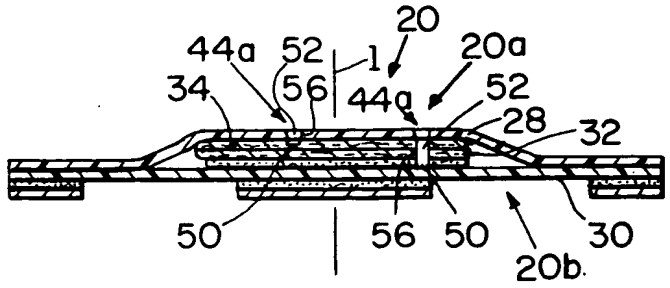

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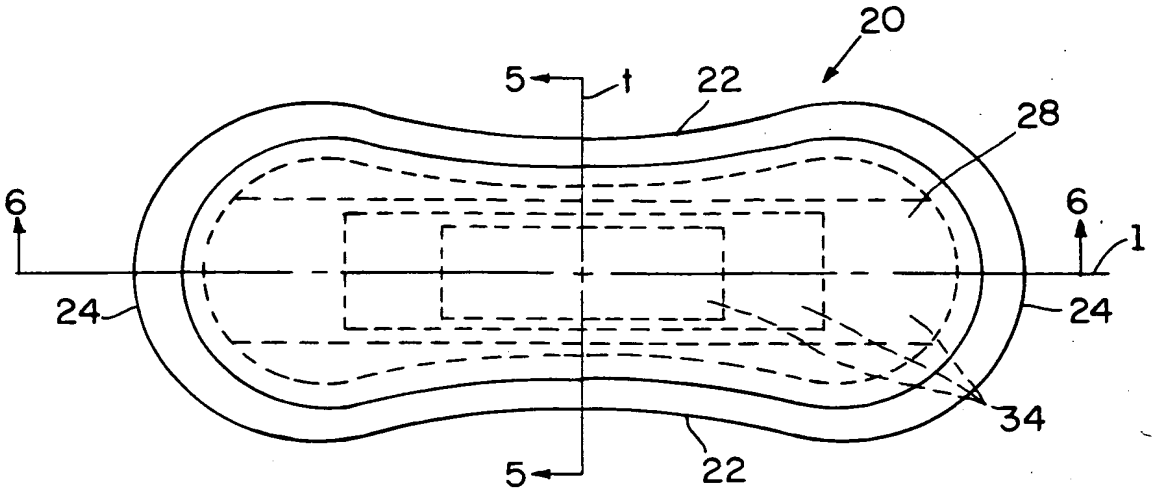
Fig. 4



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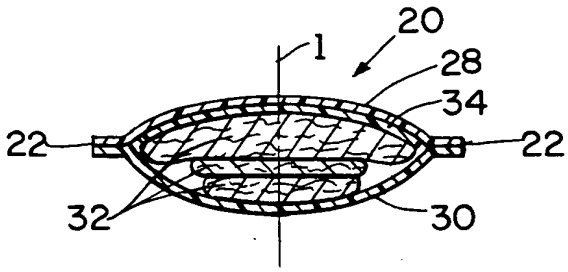

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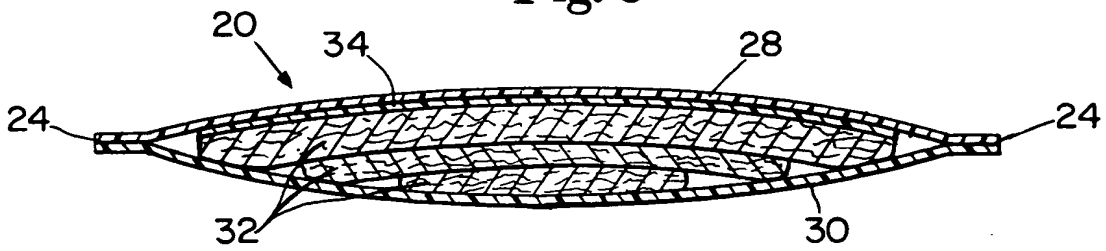

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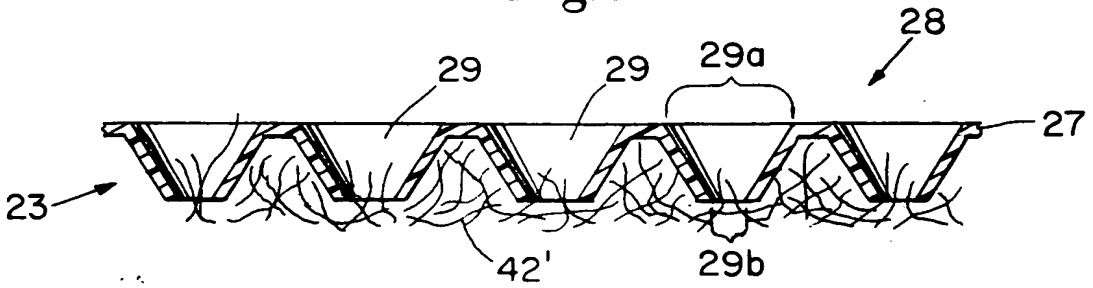

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Fig. 7A

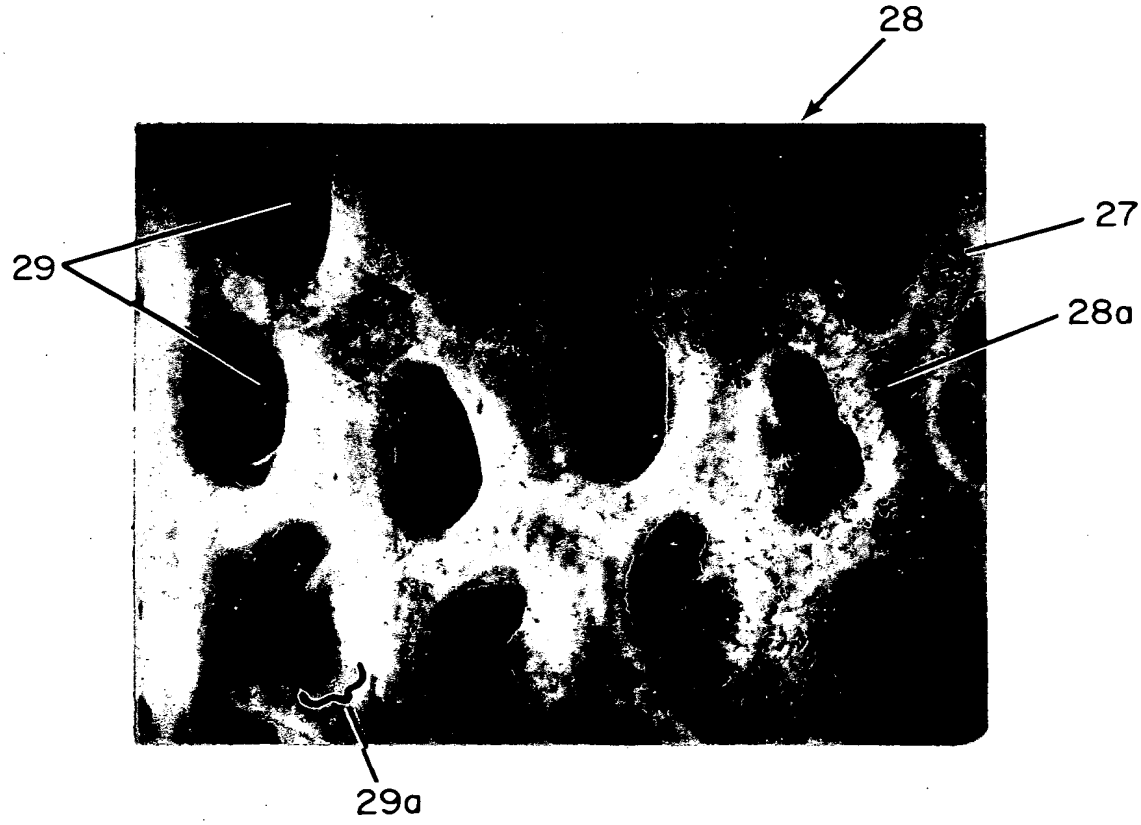

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Fig. 8

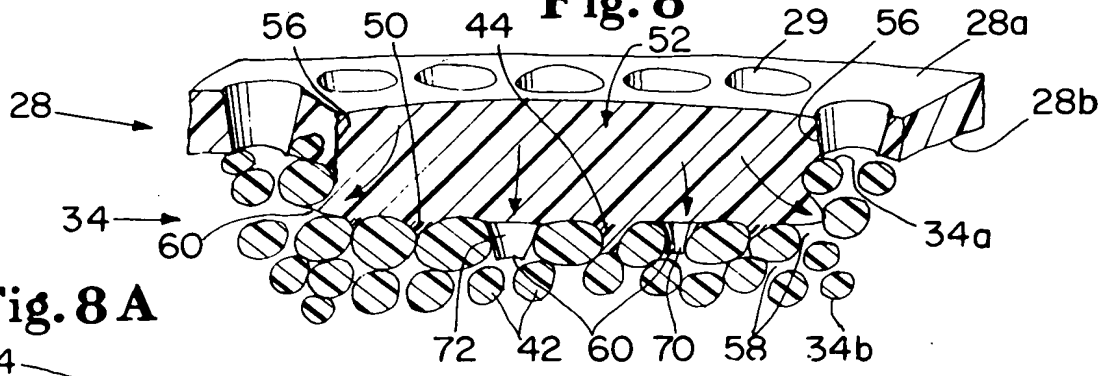
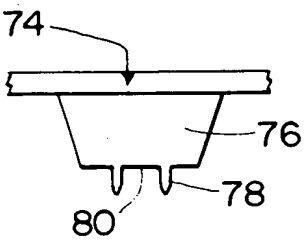


Fig. 8A



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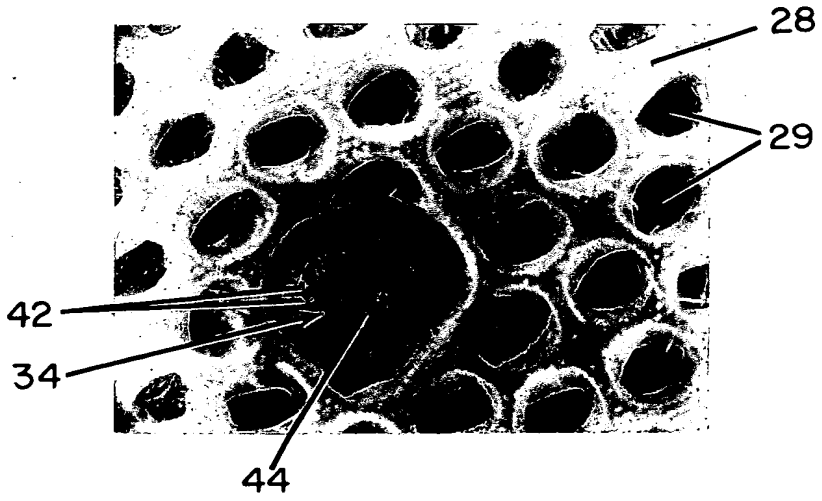

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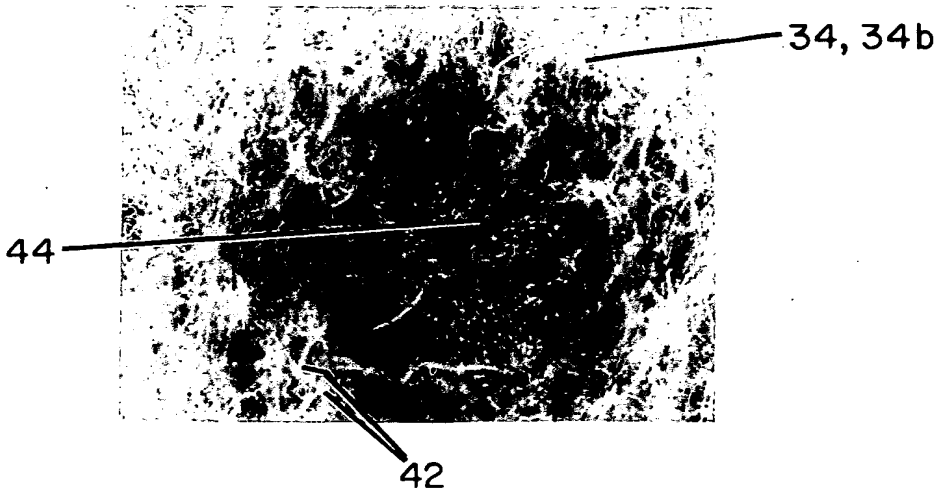

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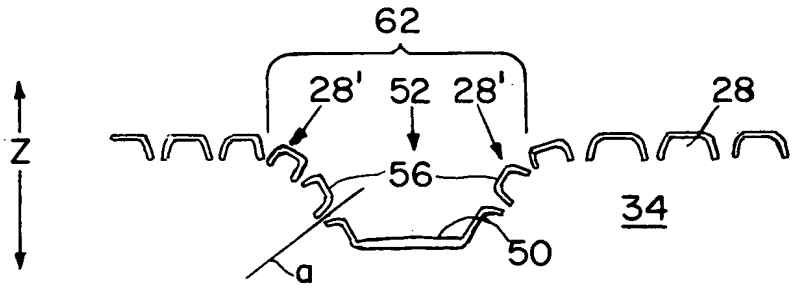
Fig. 11



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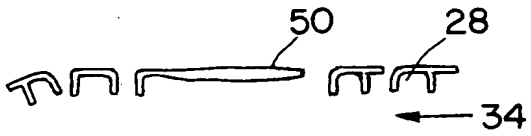

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Fig. 13A

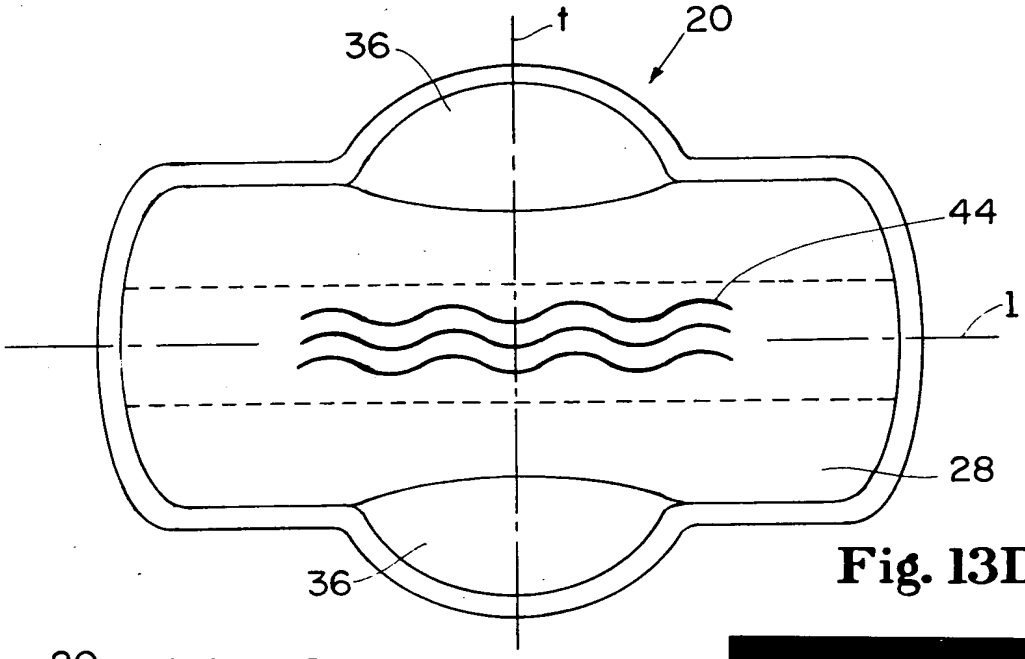

Fig. 13D

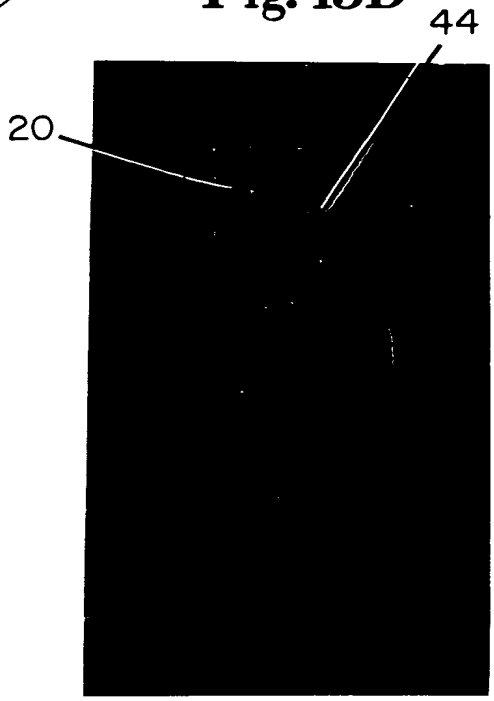

Fig. 13B

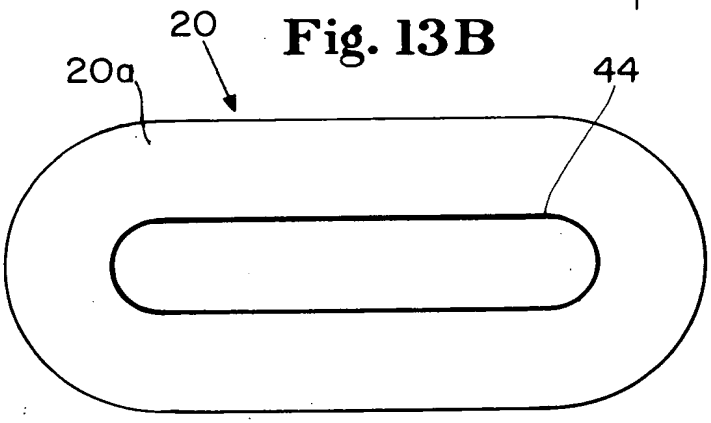

Fig. 13C

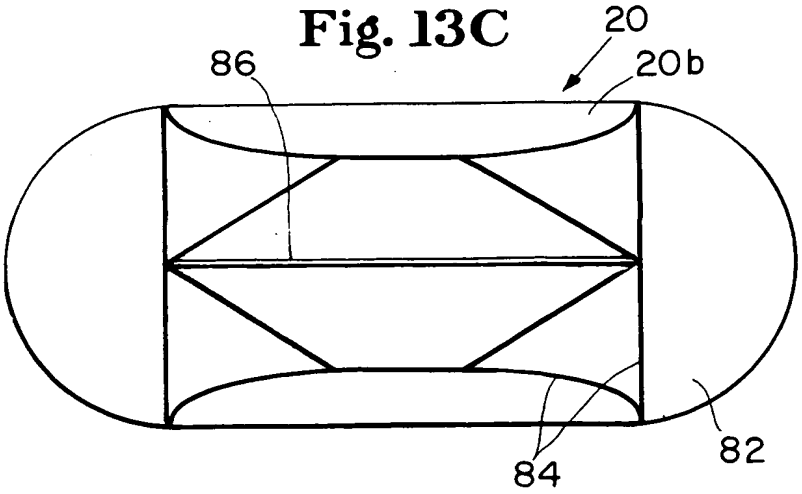

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Fig. 14

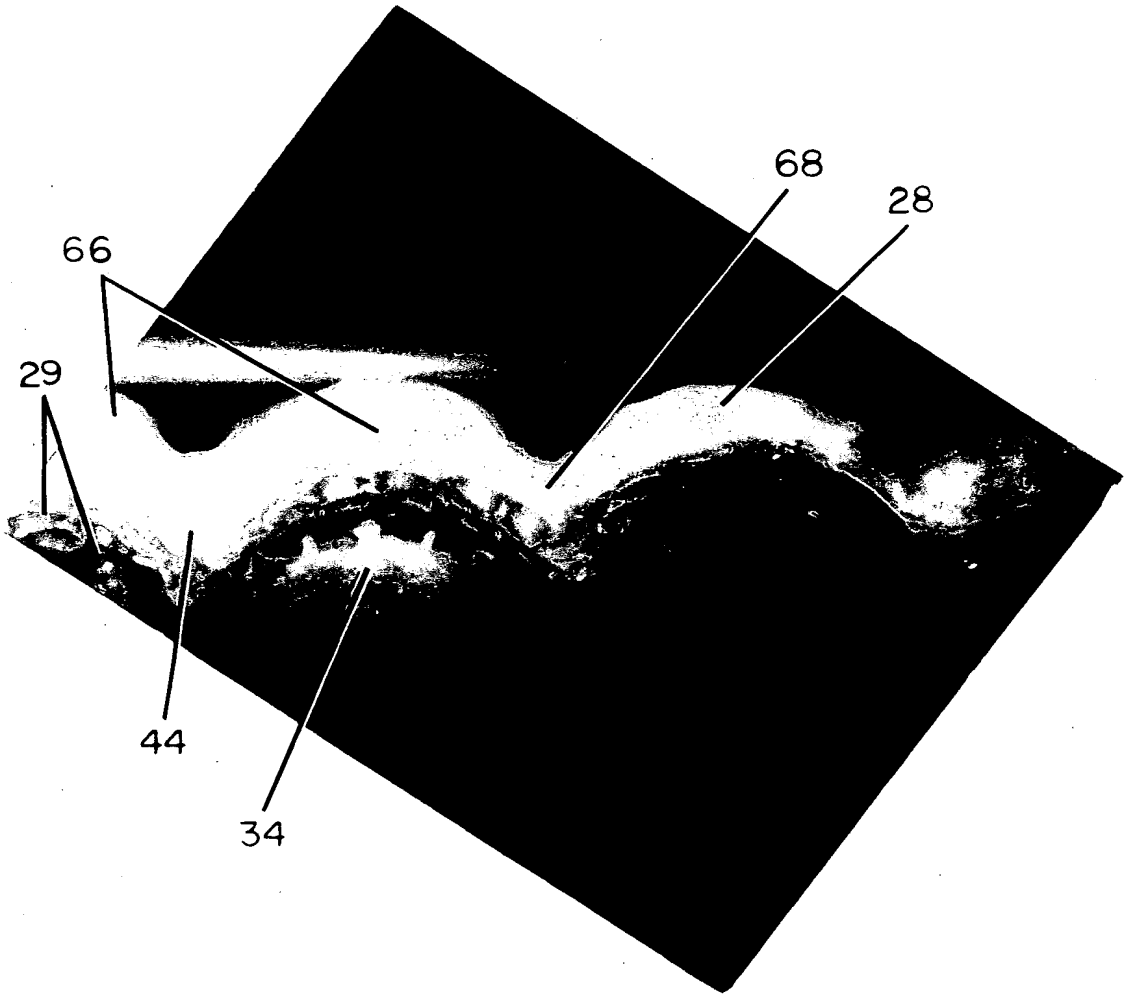

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Fig. 15

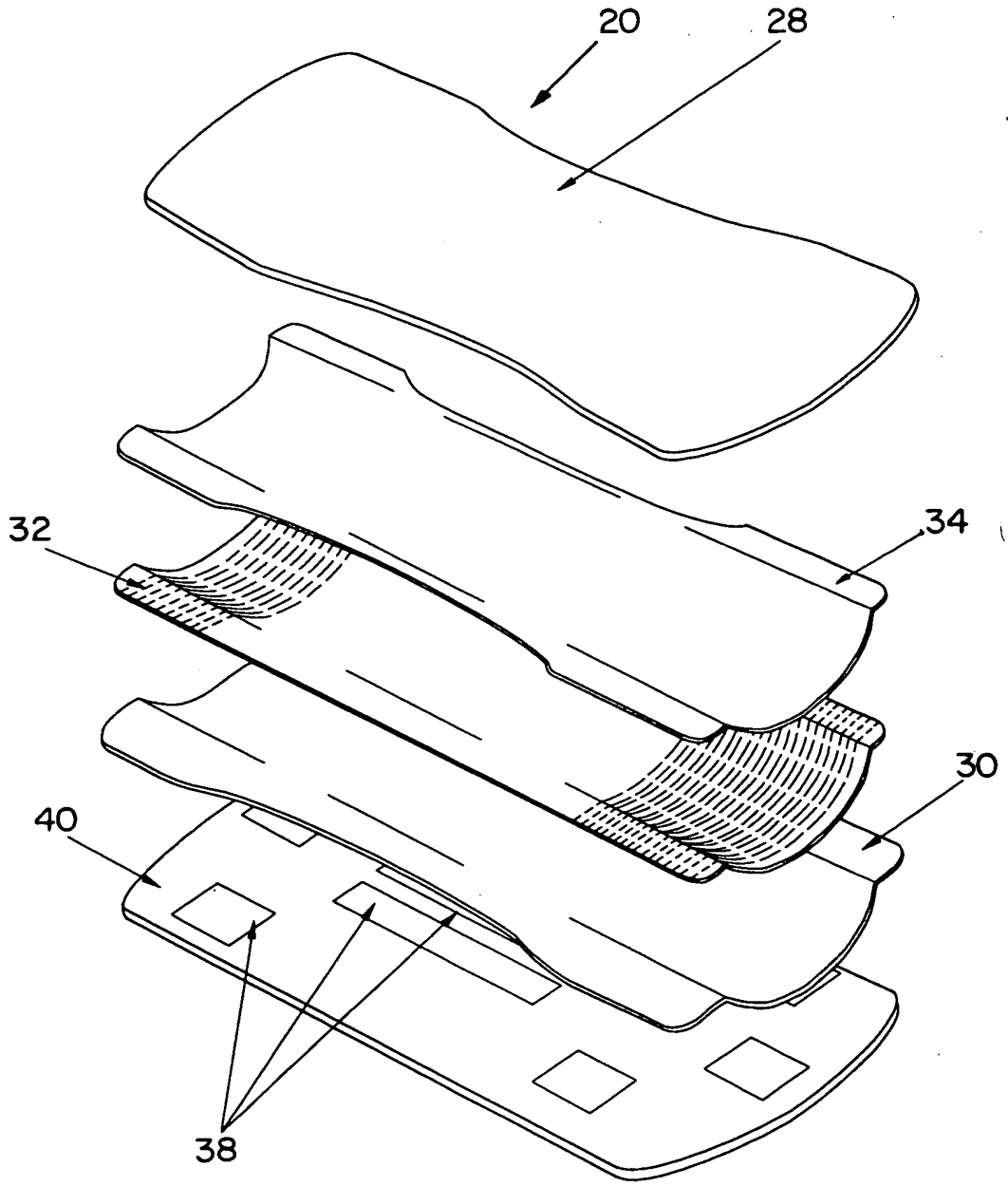

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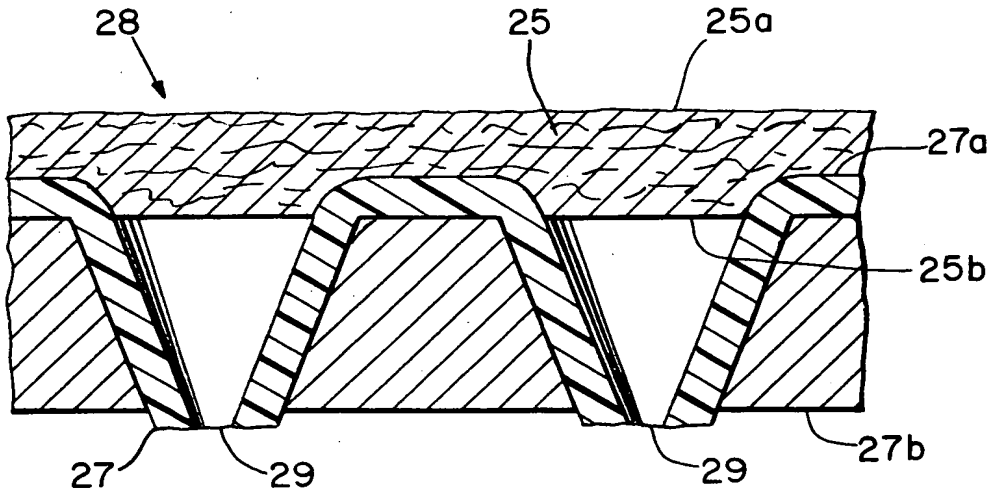
Fig. 16



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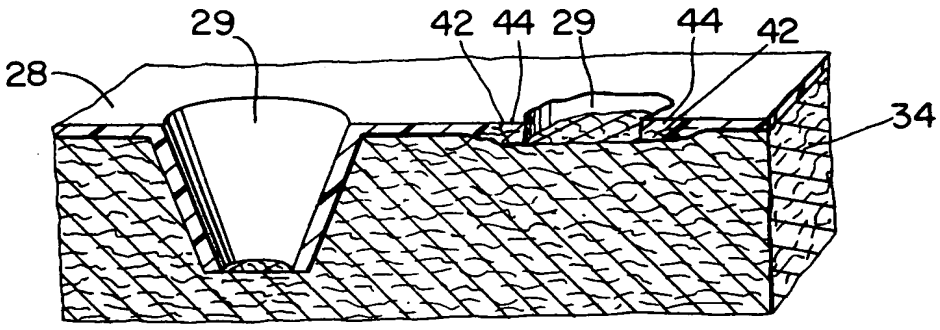

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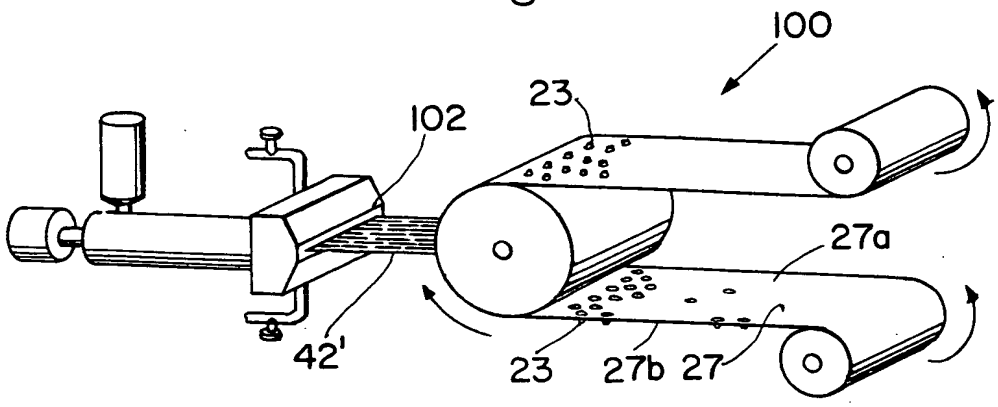
Fig. 18



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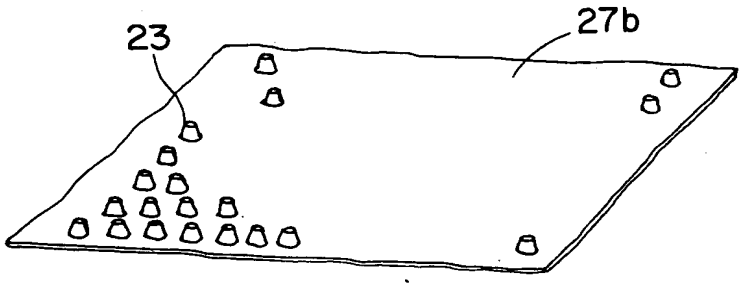

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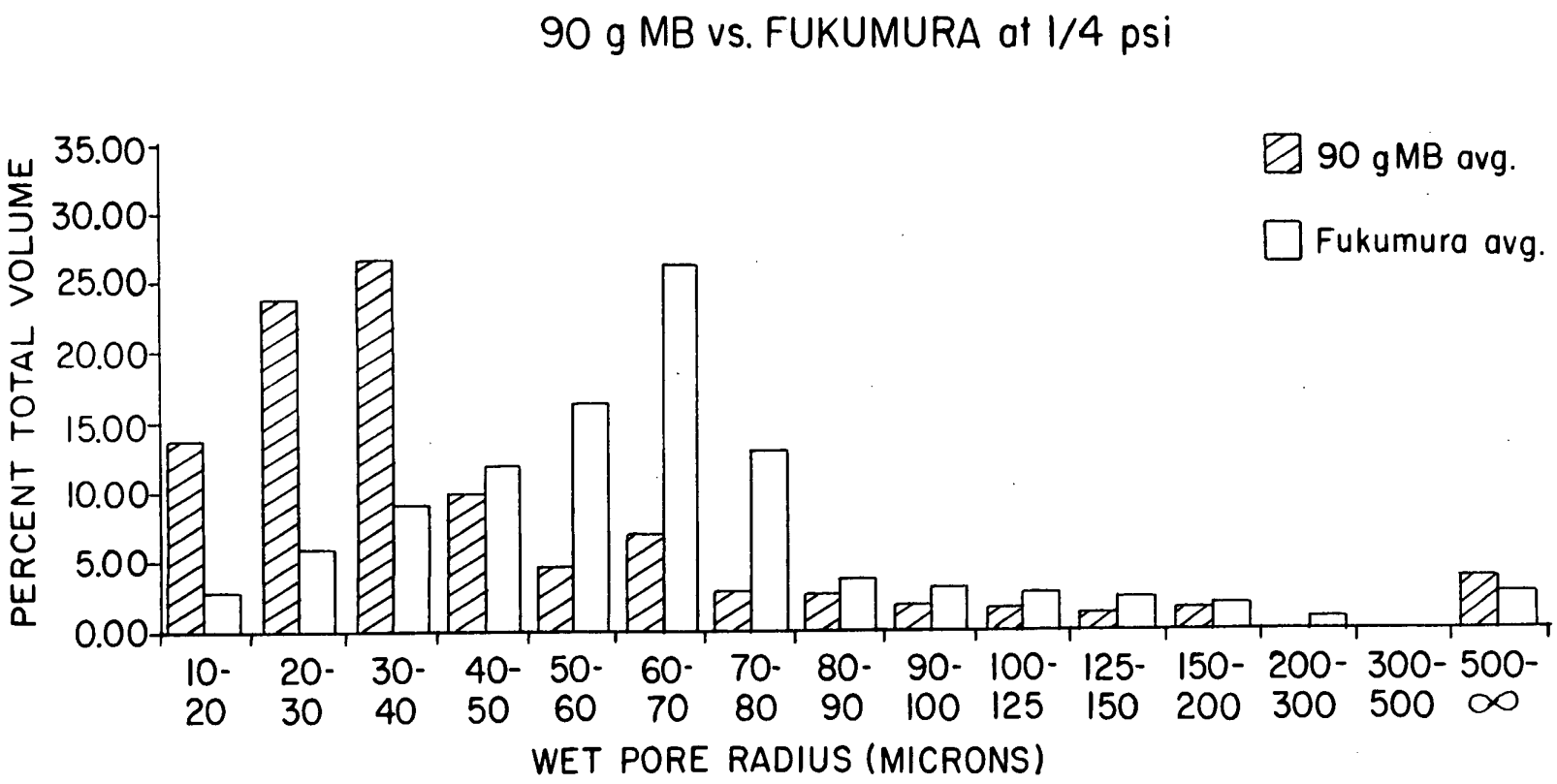
Fig. 20



Fukumura mean: 60 um
90 g MB mean: 30-40 um

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Fig. 21

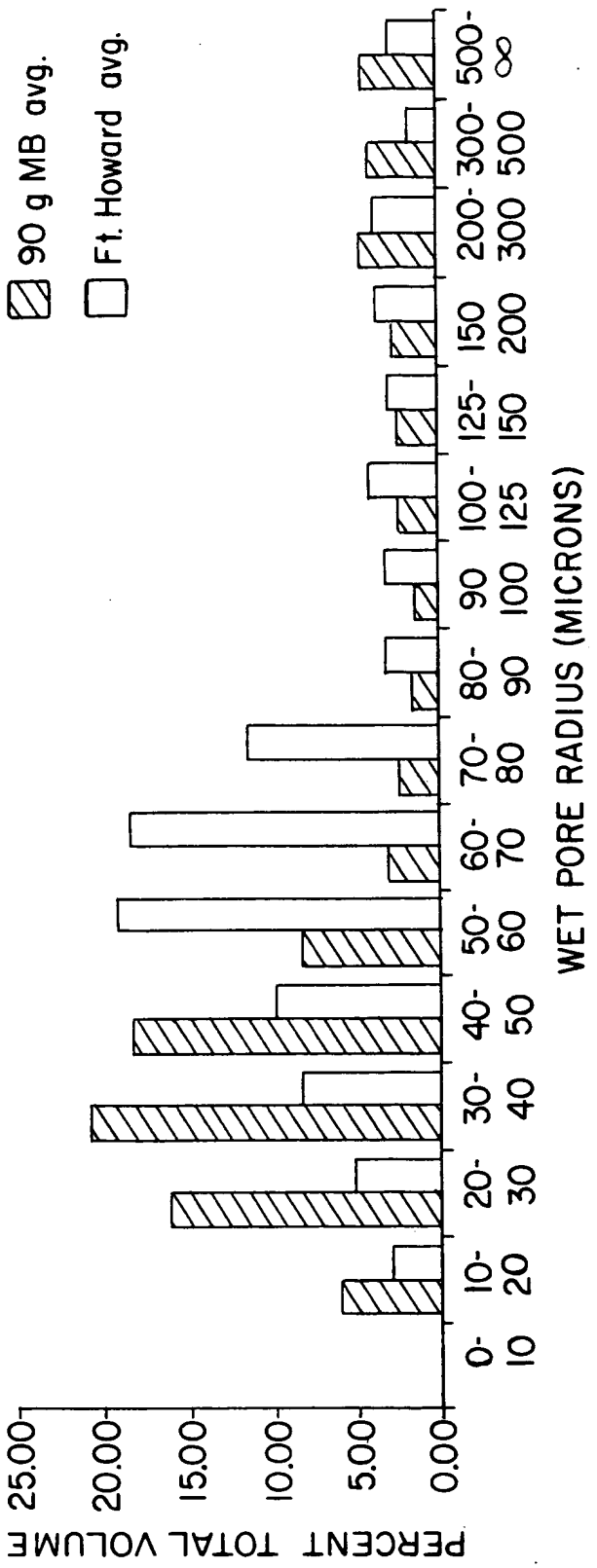

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Fig. 22

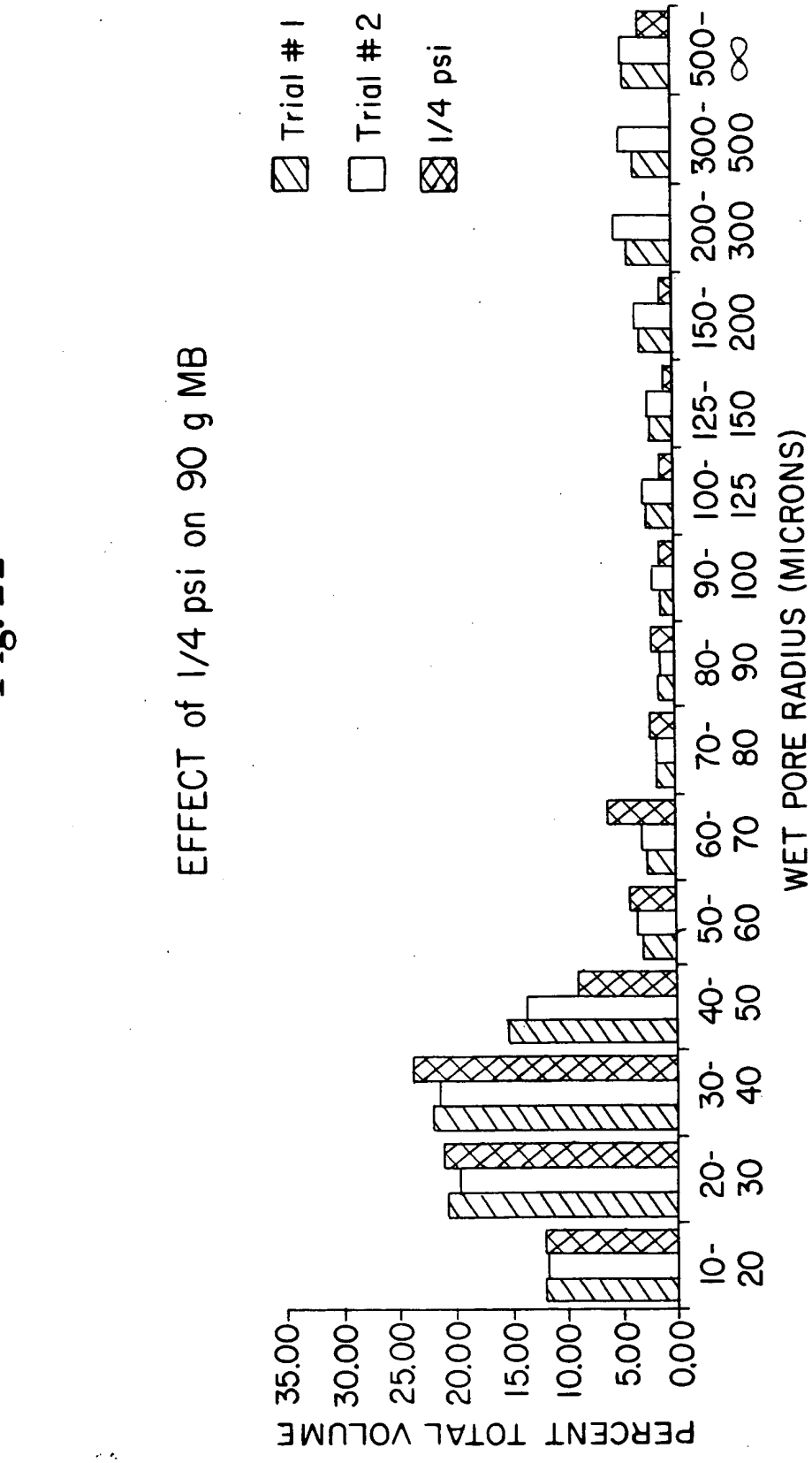

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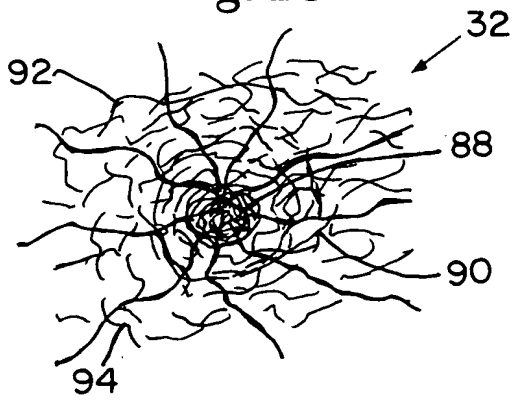
Fig. 23



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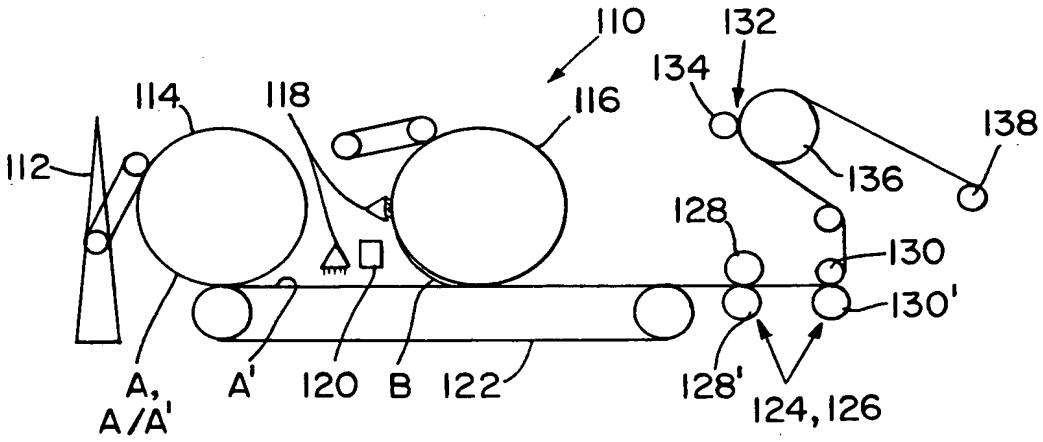

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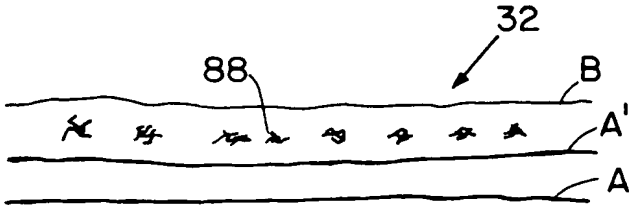

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Fig. 26

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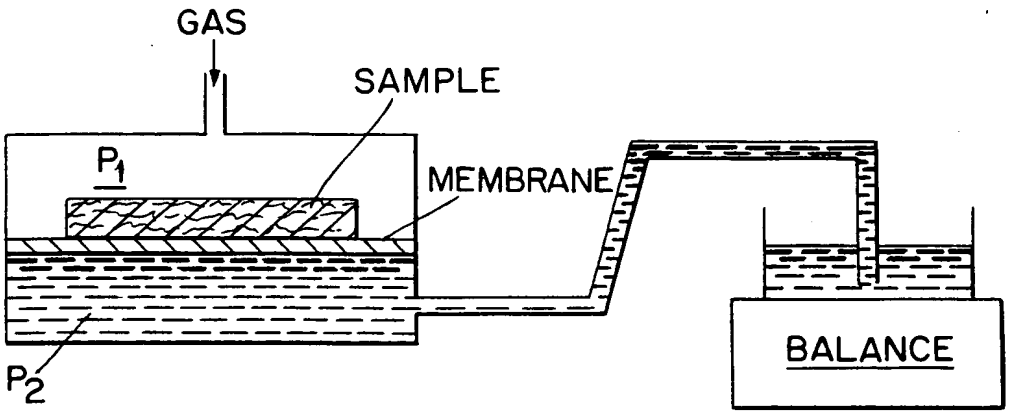
Fig. 27



$$R = \frac{2\gamma \cos\theta_{rec(adv)}}{\Delta P}$$